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What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M7
Core Size	32-Bit Single-Core
Speed	216MHz
Connectivity	CANbus, EBI/EMI, Ethernet, I ² C, IrDA, LINbus, MMC/SD/SDIO, QSPI, SAI, SPDIF, SPI, UART/USART, USB OTG
Peripherals	Brown-out Detect/Reset, DMA, I ² S, POR, PWM, WDT
Number of I/O	82
Program Memory Size	2MB (2M x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	512K x 8
Voltage - Supply (Vcc/Vdd)	1.7V ~ 3.6V
Data Converters	A/D 16x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	100-TFBGA
Supplier Device Package	100-TFBGA (8x8)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f765vih6

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2.19.3 Regulator ON/OFF and internal reset ON/OFF availability

Table 4. Regulator ON/OFF and internal reset ON/OFF availability

Package	Regulator ON	Regulator OFF	Internal reset ON	Internal reset OFF
LQFP100	Yes	No	Yes	No
LQFP144, LQFP208			Yes PDR_ON set to V _{DD}	No PDR_ON set to V _{SS}
LQFP176, UFBGA176, TFBGA216	Yes BYPASS_REG set to V _{SS}	Yes BYPASS_REG set to V _{DD}		
WLCSP180	Yes ⁽¹⁾			

1. Available only on dedicated part number. Refer to [Section 7: Ordering information](#).

2.20 Real-time clock (RTC), backup SRAM and backup registers

The RTC is an independent BCD timer/counter. It supports the following features:

- Calendar with subsecond, seconds, minutes, hours (12 or 24 format), week day, date, month, year, in BCD (binary-coded decimal) format.
- Automatic correction for 28, 29 (leap year), 30, and 31 days of the month.
- Two programmable alarms.
- On-the-fly correction from 1 to 32767 RTC clock pulses. This can be used to synchronize it with a master clock.
- Reference clock detection: a more precise second source clock (50 or 60 Hz) can be used to enhance the calendar precision.
- Digital calibration circuit with 0.95 ppm resolution, to compensate for quartz crystal inaccuracy.
- Three anti-tamper detection pins with programmable filter.
- Timestamp feature which can be used to save the calendar content. This function can be triggered by an event on the timestamp pin, or by a tamper event, or by a switch to V_{BAT} mode.
- 17-bit auto-reload wakeup timer (WUT) for periodic events with programmable resolution and period.

The RTC and the 32 backup registers are supplied through a switch that takes power either from the V_{DD} supply when present or from the V_{BAT} pin.

The backup registers are 32-bit registers used to store 128 bytes of user application data when V_{DD} power is not present. They are not reset by a system or power reset, or when the device wakes up from Standby mode.

Table 8. USART implementation (continued)

features ⁽¹⁾	USART1/2/3/6	UART4/5/7/8
Smartcard mode	X	-
Single-wire half-duplex communication	X	X
IrDA SIR ENDEC block	X	X
LIN mode	X	X
Dual clock domain	X	X
Receiver timeout interrupt	X	X
Modbus communication	X	X
Auto baud rate detection	X	X
Driver Enable	X	X

1. X: supported.

2.26 Serial peripheral interface (SPI)/inter- integrated sound interfaces (I2S)

The devices feature up to six SPIs in slave and master modes in full-duplex and simplex communication modes. SPI1, SPI4, SPI5, and SPI6 can communicate at up to 54 Mbits/s, SPI2 and SPI3 can communicate at up to 25 Mbit/s. The 3-bit prescaler gives 8 master mode frequencies and the frame is configurable from 4 to 16 bits. The SPI interfaces support NSS pulse mode, TI mode and Hardware CRC calculation. All the SPIs can be served by the DMA controller.

Three standard I²S interfaces (multiplexed with SPI1, SPI2 and SPI3) are available. They can be operated in master or slave mode, in simplex communication modes, and can be configured to operate with a 16-/32-bit resolution as an input or output channel. Audio sampling frequencies from 8 kHz up to 192 kHz are supported. When either or both of the I²S interfaces is/are configured in master mode, the master clock can be output to the external DAC/CODEC at 256 times the sampling frequency.

All I2Sx can be served by the DMA controller.

2.27 Serial audio interface (SAI)

The devices embed two serial audio interfaces.

The serial audio interface is based on two independent audio subblocks which can operate as transmitter or receiver with their FIFO. Many audio protocols are supported by each block: I2S standards, LSB or MSB-justified, PCM/DSP, TDM, AC'97 and SPDIF output, supporting audio sampling frequencies from 8 kHz up to 192 kHz. Both subblocks can be configured in master or in slave mode.

In master mode, the master clock can be output to the external DAC/CODEC at 256 times of the sampling frequency.

The two sub-blocks can be configured in synchronous mode when full-duplex mode is required.

- Refreshed by software
- DMA capability to read the final conversion data
- Interrupts: end of conversion, overrun, analog watchdog, short circuit, input serial channel clock absence
- “regular” or “injected” conversions:
 - “regular” conversions can be requested at any time or even in continuous mode without having any impact on the timing of “injected” conversions
 - “injected” conversions for precise timing and with high conversion priority

2.43 Temperature sensor

The temperature sensor has to generate a voltage that varies linearly with the temperature. The conversion range is between 1.7 V and 3.6 V. The temperature sensor is internally connected to the same input channel as V_{BAT} , ADC1_IN18, which is used to convert the sensor output voltage into a digital value. When the temperature sensor and V_{BAT} conversion are enabled at the same time, only V_{BAT} conversion is performed.

As the offset of the temperature sensor varies from chip to chip due to process variation, the internal temperature sensor is mainly suitable for applications that detect temperature changes instead of absolute temperatures. If an accurate temperature reading is needed, then an external temperature sensor part should be used.

2.44 Digital-to-analog converter (DAC)

The two 12-bit buffered DAC channels can be used to convert two digital signals into two analog voltage signal outputs.

This dual digital Interface supports the following features:

- Two DAC converters: one for each output channel
- 8-bit or 12-bit monotonic output
- Left or right data alignment in 12-bit mode
- Synchronized update capability
- Noise-wave generation
- Triangular-wave generation
- Dual DAC channel independent or simultaneous conversions
- DMA capability for each channel
- External triggers for conversion
- Input voltage reference V_{REF+}

Eight DAC trigger inputs are used in the device. The DAC channels are triggered through the timer update outputs that are also connected to different DMA streams.

2.45 Serial wire JTAG debug port (SWJ-DP)

The ARM SWJ-DP interface is embedded, and is a combined JTAG and serial wire debug port that enables either a serial wire debug or a JTAG probe to be connected to the target.

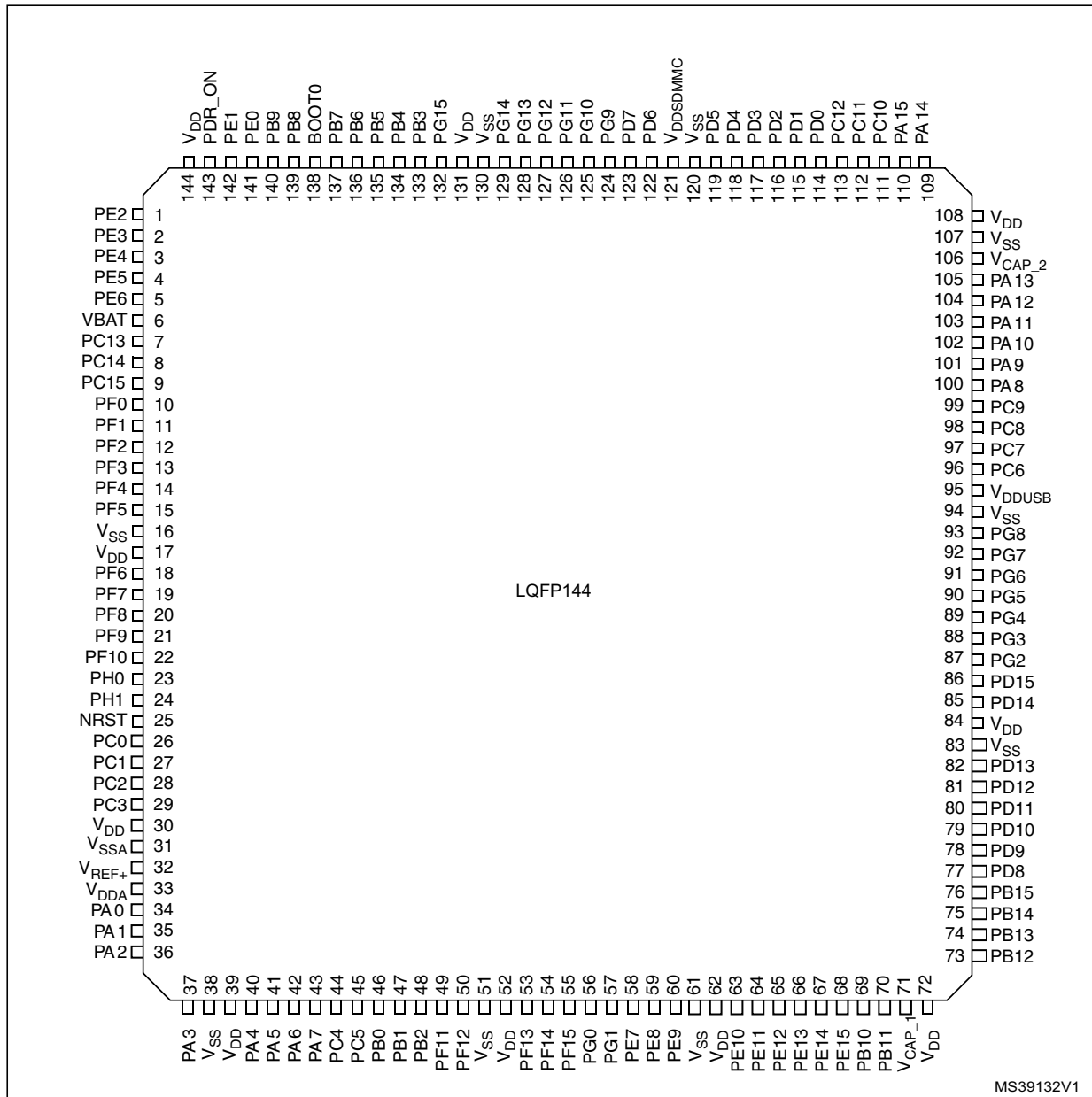
The debug is performed using 2 pins only instead of 5 required by the JTAG (JTAG pins could be re-use as GPIO with alternate function): the JTAG TMS and TCK pins are shared with SWDIO and SWCLK, respectively, and a specific sequence on the TMS pin is used to switch between JTAG-DP and SW-DP.

2.46 Embedded Trace Macrocell™

The ARM Embedded Trace Macrocell provides a greater visibility of the instruction and data flow inside the CPU core by streaming compressed data at a very high rate from the STM32F76xxx through a small number of ETM pins to an external hardware trace port analyzer (TPA) device. The TPA is connected to a host computer using USB, Ethernet, or any other high-speed channel. Real-time instruction and data flow activity can be recorded and then formatted for display on the host computer that runs the debugger software. TPA hardware is commercially available from common development tool vendors.

The Embedded Trace Macrocell operates with third party debugger software tools.

Figure 12. STM32F76xxx LQFP144 pinout



1. The above figure shows the package top view.

1. NC (not-connected) pins are not bonded. They must be configured by software to output push-pull and forced to 0 in the output data register to avoid an extra current consumption in low-power modes. list of pins: PI8, PI12, PI13, PI14, PF6, PF7, PF8, PF9, PC2, PC3, PC4, PC5, PI15, PJ0, PJ1, PJ2, PJ3, PJ4, PJ5, PH6, PH7, PJ12, PJ13, PJ14, PJ15, PG14, PK3, PK4, PK5, PK6 and PK7.
2. PC13, PC14, PC15 and PI8 are supplied through the power switch. Since the switch only sinks a limited amount of current (3 mA), the use of GPIOs PC13 to PC15 and PI8 in output mode is limited: - The speed should not exceed 2 MHz with a maximum load of 30 pF. - These I/Os must not be used as a current source (e.g. to drive an LED).
3. FT = 5 V tolerant except when in analog mode or oscillator mode (for PC14, PC15, PH0 and PH1).
4. If the device is in regulator OFF/internal reset ON mode (BYPASS_REG pin is set to VDD), then PA0 is used as an internal reset (active low).
5. Internally connected to VDD or VSS depending on part number.



Table 12. STM32F765xx, STM32F767xx, STM32F768Ax and STM32F769xx alternate function mapping (continued)

Port		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
		SYS	I2C4/UART5/TIM1/2	TIM3/4/5	TIM8/9/10/11/LPTIM1/DFSDM1/CEC	I2C1/2/3/4/USART1/CEC	SPI1/I2S1/SPI2/I2S2/SPI3/I2S3/SPI4/5/6	SPI2/I2S2/SPI3/I2S3/SAI1/I2C4/UART4/DFSDM1	SPI2/I2S2/SPI3/I2S3/SPI6/USART1/2/3/UART5/DFSDM1/SPDIF	SPI6/SAI2/USART6/UART4/5/7/8/OTG_FS/SPDIF	CAN1/2/TIM12/13/14/QUADSPI/FMC/LCD	SAI2/QUADSPI/SDMMC2/DFSDM1/OTG2_HS/OTG1_FS/LCD	I2C4/CAN3/SDMMC2/ETH	UART7/FMC/SDMMC1/MDIOS/OTG2_FS	DCMI/LCD/DSI	LCD	SYS
Port J	PJ11	-	-	-	-	-	-	-	-	-	-	-	-	-	-	LCD_G4	EVEN TOUT
	PJ12	-	-	-	-	-	-	-	-	-	LCD_G3	-	-	-	-	LCD_B0	EVEN TOUT
	PJ13	-	-	-	-	-	-	-	-	-	LCD_G4	-	-	-	-	LCD_B1	EVEN TOUT
	PJ14	-	-	-	-	-	-	-	-	-	-	-	-	-	-	LCD_B2	EVEN TOUT
	PJ15	-	-	-	-	-	-	-	-	-	-	-	-	-	-	LCD_B3	EVEN TOUT
Port K	PK0	-	-	-	-	-	-	-	-	-	-	-	-	-	-	LCD_G5	EVEN TOUT
	PK1	-	-	-	-	-	-	-	-	-	-	-	-	-	-	LCD_G6	EVEN TOUT
	PK2	-	-	-	-	-	-	-	-	-	-	-	-	-	-	LCD_G7	EVEN TOUT
	PK3	-	-	-	-	-	-	-	-	-	-	-	-	-	-	LCD_B4	EVEN TOUT
	PK4	-	-	-	-	-	-	-	-	-	-	-	-	-	-	LCD_B5	EVEN TOUT
	PK5	-	-	-	-	-	-	-	-	-	-	-	-	-	-	LCD_B6	EVEN TOUT
	PK6	-	-	-	-	-	-	-	-	-	-	-	-	-	-	LCD_B7	EVEN TOUT
	PK7	-	-	-	-	-	-	-	-	-	-	-	-	-	-	LCD_DE	EVEN TOUT

Table 13. STM32F765xx, STM32F767xx, STM32F768Ax and STM32F769xx register boundary addresses⁽¹⁾ (continued)

Bus	Boundary address	Peripheral
	0x4001 7C00 - 0x4001 FFFF	Reserved
APB2	0x4001 7800 - 0x4001 7BFF	MDIOS
	0x4001 7400 - 0x4001 77FF	DFSDM1
	0x4001 6C00 - 0x4001 73FF	DSI Host
	0x4001 6800 - 0x4001 6BFF	LCD-TFT
	0x4001 6000 - 0x4001 67FF	Reserved
	0x4001 5C00 - 0x4001 5FFF	SAI2
	0x4001 5800 - 0x4001 5BFF	SAI1
	0x4001 5400 - 0x4001 57FF	SPI6
	0x4001 5000 - 0x4001 53FF	SPI5
	0x4001 4C00 - 0x4001 4FFF	Reserved
	0x4001 4800 - 0x4001 4BFF	TIM11
	0x4001 4400 - 0x4001 47FF	TIM10
	0x4001 4000 - 0x4001 43FF	TIM9
	0x4001 3C00 - 0x4001 3FFF	EXTI
	0x4001 3800 - 0x4001 3BFF	SYSCFG
	0x4001 3400 - 0x4001 37FF	SPI4
	0x4001 3000 - 0x4001 33FF	SPI1/I2S1
	0x4001 2C00 - 0x4001 2FFF	SDMMC1
	0x4001 2400 - 0x4001 2BFF	Reserved
	0x4001 2000 - 0x4001 23FF	ADC1 - ADC2 - ADC3
	0x4001 1C00 - 0x4001 1FFF	SDMMC2
	0x4001 1800 - 0x4001 1BFF	Reserved
	0x4001 1400 - 0x4001 17FF	USART6
	0x4001 1000 - 0x4001 13FF	USART1
	0x4001 0800 - 0x4001 0FFF	Reserved
	0x4001 0400 - 0x4001 07FF	TIM8
0x4001 0000 - 0x4001 03FF	TIM1	

Table 29. Typical and maximum current consumption in Run mode, code with data processing running from Flash memory (Single bank mode) on ITCM interface (ART disabled), regulator ON

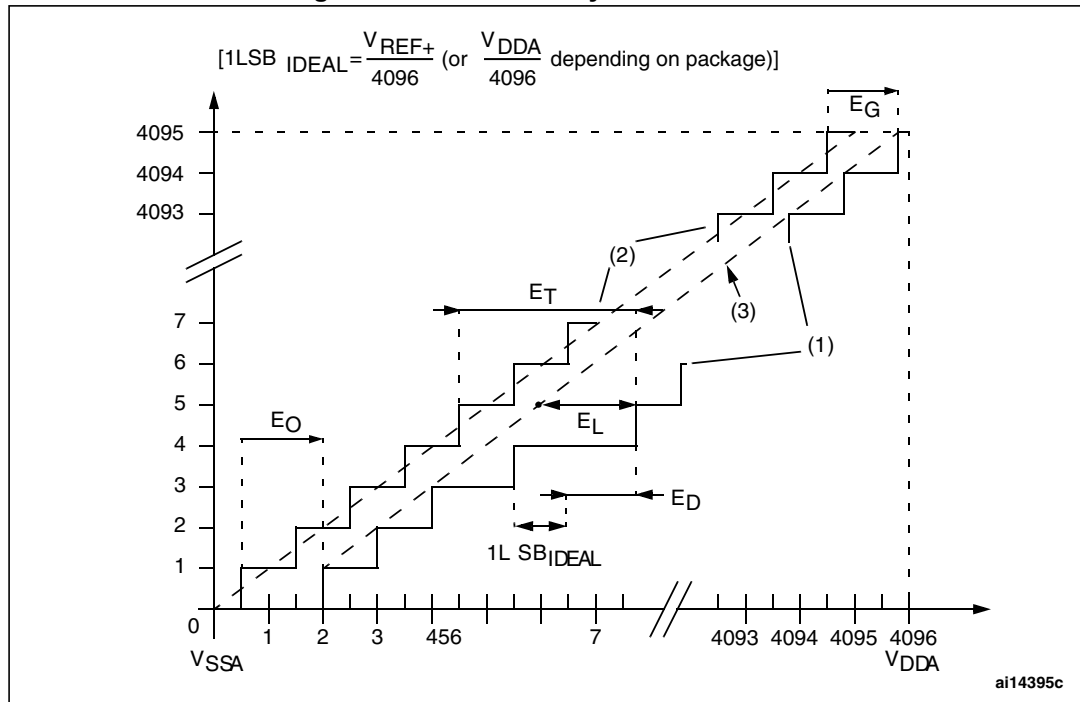
Symbol	Parameter	Conditions	f _{HCLK} (MHz)	Typ	Max ⁽¹⁾			Unit
					TA= 25 °C	TA=85 °C	TA=105 °C	
I _{DD}	Supply current in RUN mode	All peripherals enabled ⁽²⁾⁽³⁾	216	215	242	281	-	mA
			200	200	218	265	293	
			180	185	200	237	258	
			168	166	179	213	233	
			144	134	144	172	190	
			60	61	68	95	112	
			25	29	34	61	78	
		All peripherals disabled ⁽³⁾	216	118	129	177	-	
			200	110	120	168	196	
			180	104	113	149	170	
			168	94	102	135	155	
			144	79	85	113	130	
			60	37	42	69	86	
			25	18	22	48	66	

1. Guaranteed by characterization results, unless otherwise specified.
2. When analog peripheral blocks such as ADCs, DACs, HSE, LSE, HSI, or LSI are ON, an additional power consumption should be considered.
3. When the ADC is ON (ADON bit set in the ADC_CR2 register), add an additional power consumption of 1.73 mA per ADC for the analog part.

Table 39. Peripheral current consumption

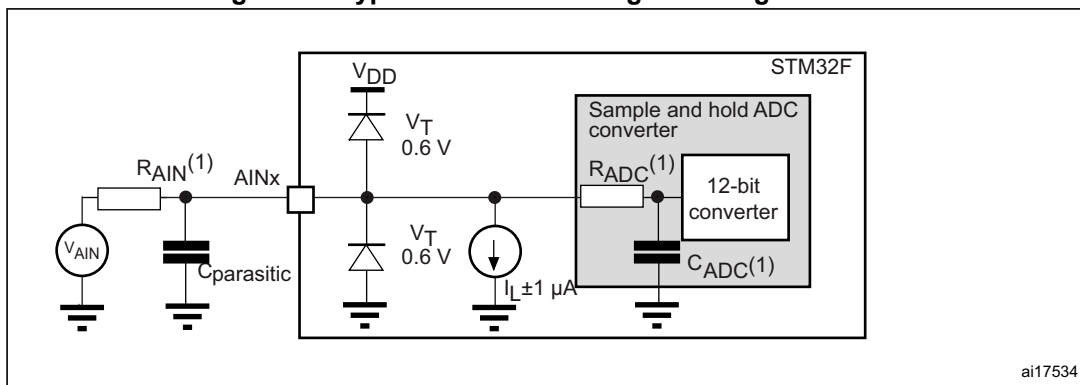
Peripheral		I _{DD} (Typ) ⁽¹⁾			Unit
		Scale 1	Scale 2	Scale 3	
AHB1 (up to 216 MHz)	GPIOA	2.9	2.8	2.2	μA/MHz
	GPIOB	3.0	2.9	2.2	
	GPIOC	2.9	2.8	2.2	
	GIPOD	3.1	3.0	2.3	
	GPIOE	3.1	3.0	2.3	
	GPIOF	2.9	2.8	2.2	
	GPIOG	2.9	2.8	2.2	
	GPIOH	3.1	3.1	2.4	
	GPIOI	3.0	2.9	2.2	
	GPIOJ	2.9	2.9	2.2	
	GPIOK	2.8	2.8	2.4	
	CRC	1.0	0.9	0.8	
	BKPSRAM	0.9	0.9	0.7	
	DMA1	3.17 x N + 11.63	3.08 x N + 11.39	2.6 x N + 9.64	
	DMA2	3.33 x N + 12.84	3.27 x N + 11.84	2.75 x N + 10.10	
	DMA2D	77.7	76.3	63.5	
ETH_MAC ETH_MAC_TX ETH_MAC_RX ETH_MAC_PTP	40.1	39.5	32.8		
OTG_HS	58.5	57.4	48.1		
OTG_HS+ULPI	58.5	57.4	48.1		
AHB2 (up to 216 MHz)	DCMI	2.9	2.8	2.1	μA/MHz
	JPEG	74.8	73.4	61.9	
	RNG	6.7	6.7	5.4	
	USB_OTG_FS	32.4	31.9	26.7	
AHB3 (up to 216 MHz)	FMC	18.6	18.2	15.1	μA/MHz
	QSPI	22.3	21.8	18.1	
Bus matrix ⁽²⁾		3.94	3.25	2.12	μA/MHz

Figure 41. ADC accuracy characteristics



1. See also [Table 73](#).
2. Example of an actual transfer curve.
3. Ideal transfer curve.
4. End point correlation line.
5. E_T = Total Unadjusted Error: maximum deviation between the actual and the ideal transfer curves.
 E_O = Offset Error: deviation between the first actual transition and the first ideal one.
 E_G = Gain Error: deviation between the last ideal transition and the last actual one.
 E_D = Differential Linearity Error: maximum deviation between actual steps and the ideal one.
 E_L = Integral Linearity Error: maximum deviation between any actual transition and the end point correlation line.

Figure 42. Typical connection diagram using the ADC



1. Refer to [Table 71](#) for the values of R_{AIN} , R_{ADC} and C_{ADC} .
2. $C_{parasitic}$ represents the capacitance of the PCB (dependent on soldering and PCB layout quality) plus the pad capacitance (roughly 5 pF). A high $C_{parasitic}$ value downgrades conversion accuracy. To remedy this, f_{ADC} should be reduced.

The SDA and SCL I/O requirements are met with the following restrictions:

- The SDA and SCL I/O pins are not “true” open-drain. When configured as open-drain, the PMOS connected between the I/O pin and V_{DD} is disabled, but is still present.
- The 20mA output drive requirement in Fast-mode Plus is not supported. This limits the maximum load C_{load} supported in Fm+, which is given by these formulas:

$$Tr(SDA/SCL) = 0.8473 \times R_p \times C_{load}$$

$$R_p(\min) = (V_{DD} - V_{OL}(\max)) / I_{OL}(\max)$$

Where R_p is the I2C lines pull-up. Refer to [Section 5.3.20: I/O port characteristics](#) for the I2C I/Os characteristics.

All I²C SDA and SCL I/Os embed an analog filter. Refer to [Table 84](#) for the analog filter characteristics:

Table 84. I2C analog filter characteristics⁽¹⁾

Symbol	Parameter	Min	Max	Unit
t _{AF}	Maximum pulse width of spikes that are suppressed by the analog filter	50 ⁽²⁾	70 ⁽³⁾	ns

1. Guaranteed by characterization results.
2. Spikes with widths below t_{AF(min)} are filtered.
3. Spikes with widths above t_{AF(max)} are not filtered.

JTAG/SWD characteristics

Unless otherwise specified, the parameters given in [Table 87](#) for JTAG/SWD are derived from tests performed under the ambient temperature, f_{HCLK} frequency and VDD supply voltage conditions summarized in [Table 17](#), with the following configuration:

- Output speed is set to OSPEEDRy[1:0] = 10
- Capacitive load C=30 pF
- Measurement points are performed at CMOS levels: $0.5V_{\text{DD}}$

Refer to [Section 5.3.20: I/O port characteristics](#) for more details on the input/output alternate function characteristics (SCK,SD,WS).

Table 87. Dynamics characteristics: JTAG characteristics

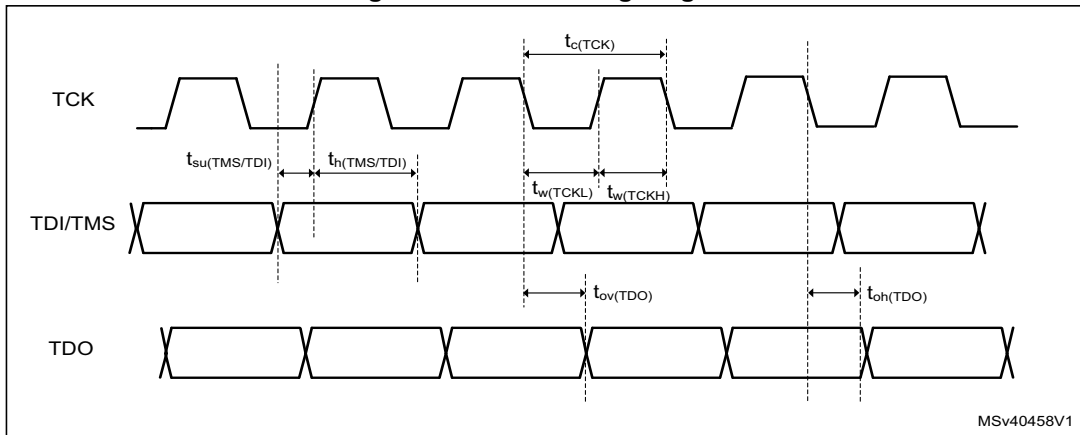
Symbol	Parameter	Conditions	Min	Typ	Max	Unit
F_{pp}	TCK clock frequency	2.7V <VDD< 3.6V	-	-	40	MHz
$1/t_{\text{c(TCK)}}$		1.71 <VDD< 3.6V	-	-	35	
$t_{\text{w(TCKH)}}$ $t_{\text{w(TCKL)}}$	SCK high and low time	-	$T_{\text{PCLK}} - 1$	T_{PCLK}	$T_{\text{PCLK}} + 1$	ns
$t_{\text{su(TMS)}}$	TMS input setup time	-	3	-	-	
$t_{\text{h(TMS)}}$	TMS input hold time	-	0	-	-	
$t_{\text{su(TDI)}}$	TDI input setup time	-	0.5	-	-	
$t_{\text{h(TDI)}}$	TDI input hold time	-	2	-	-	
$t_{\text{ov(TDO)}}$	TDO output valid time	2.7V <VDD< 3.6V	-	9	11	
		1.71 <VDD< 3.6V	-	9	13	
$t_{\text{oh(TDO)}}$	TDO output hold time	-	7.5	-	-	

Table 88. Dynamics characteristics: SWD characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
F_{pp}	SWCLK clock frequency	2.7V <VDD< 3.6V	-	-	80	MHz
$1/t_{c(SWCLK)}$		1.71 <VDD< 3.6V	-	-	50	
$t_{w(SWCLKH)}$ $t_{w(SWCLKL)}$	SCK high and low time	-	$T_{PCLK} - 1$	T_{PCLK}	$T_{PCLK} + 1$	ns
$t_{su(SWDIO)}$	SWDIO input setup time	-	3.5	-	-	
$t_{h(SWDIO)}$	SWDIO input hold time	-	0	-	-	
$t_{ov(SWDIO)}$	SWDIO output valid time	2.7V <VDD< 3.6V	-	11	12	
		1.71 <VDD< 3.6V	-	11	16.5	
$t_{oh(SWDIO)}$	SWDIO output hold time	-	9	-	-	

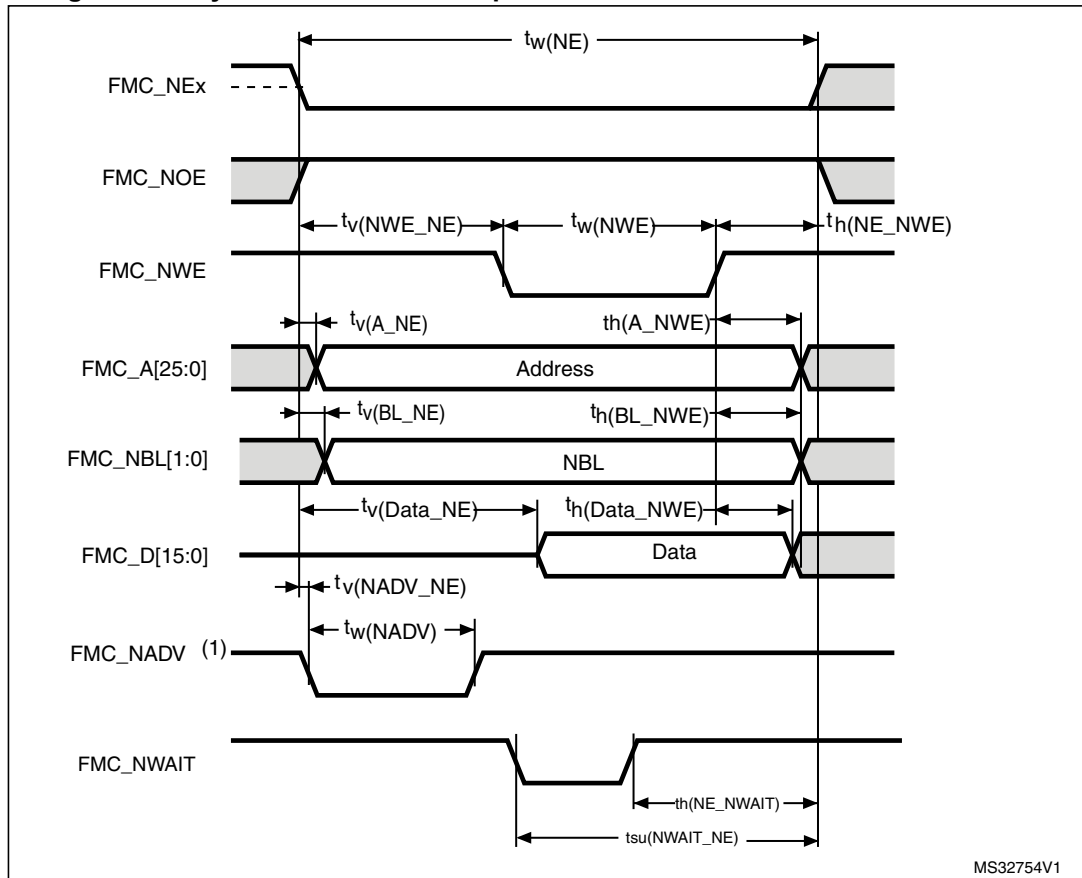
JTAG/SWD timing diagrams

Figure 51. JTAG timing diagram



MSv40458V1

Figure 62. Asynchronous non-multiplexed SRAM/PSRAM/NOR write waveforms



MS32754V1

1. Mode 2/B, C and D only. In Mode 1, FMC_NADV is not used.

Table 102. Asynchronous non-multiplexed SRAM/PSRAM/NOR write timings⁽¹⁾

Symbol	Parameter	Min	Max	Unit
$t_{w(NE)}$	FMC_NE low time	$3T_{HCLK} - 1$	$3T_{HCLK} + 1$	ns
$t_{v(NWE_NE)}$	FMC_NEx low to FMC_NWE low	$T_{HCLK} - 1$	$T_{HCLK} + 0.5$	
$t_{w(NWE)}$	FMC_NWE low time	$T_{HCLK} - 1.5$	$T_{HCLK} + 0.5$	
$t_{h(NE_NWE)}$	FMC_NWE high to FMC_NE high hold time	T_{HCLK}	-	
$t_{v(A_NE)}$	FMC_NEx low to FMC_A valid	-	0	
$t_{h(A_NWE)}$	Address hold time after FMC_NWE high	$T_{HCLK} - 0.5$	-	
$t_{v(BL_NE)}$	FMC_NEx low to FMC_BL valid	-	0.5	
$t_{h(BL_NWE)}$	FMC_BL hold time after FMC_NWE high	$T_{HCLK} - 0.5$	-	
$t_{v(Data_NE)}$	Data to FMC_NEx low to Data valid	-	$T_{HCLK} + 2$	
$t_{h(Data_NWE)}$	Data hold time after FMC_NWE high	$T_{HCLK} + 0.5$	-	
$t_{v(NADV_NE)}$	FMC_NEx low to FMC_NADV low	-	0	
$t_{w(NADV)}$	FMC_NADV low time	-	$T_{HCLK} + 1$	

1. Guaranteed by characterization results.

Figure 66. Synchronous multiplexed PSRAM write timings

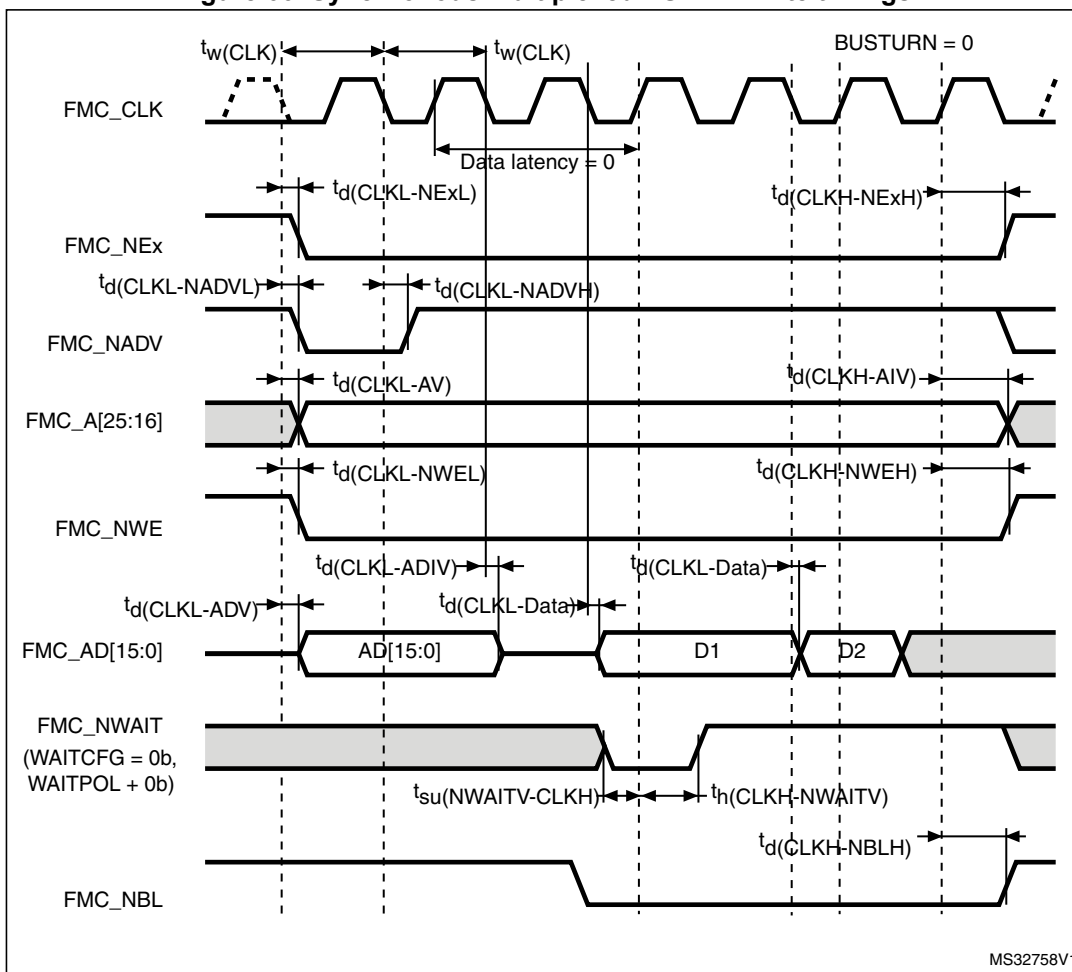
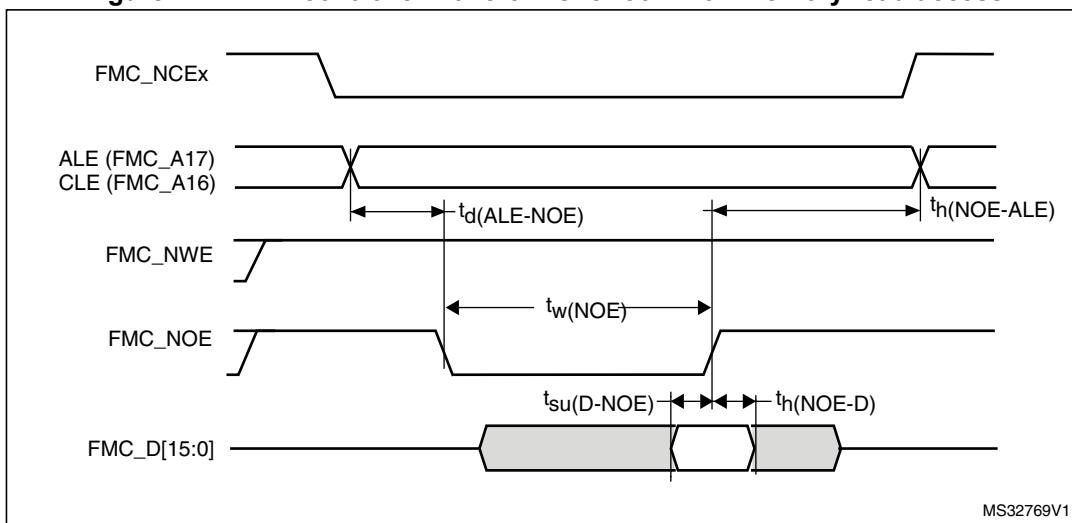
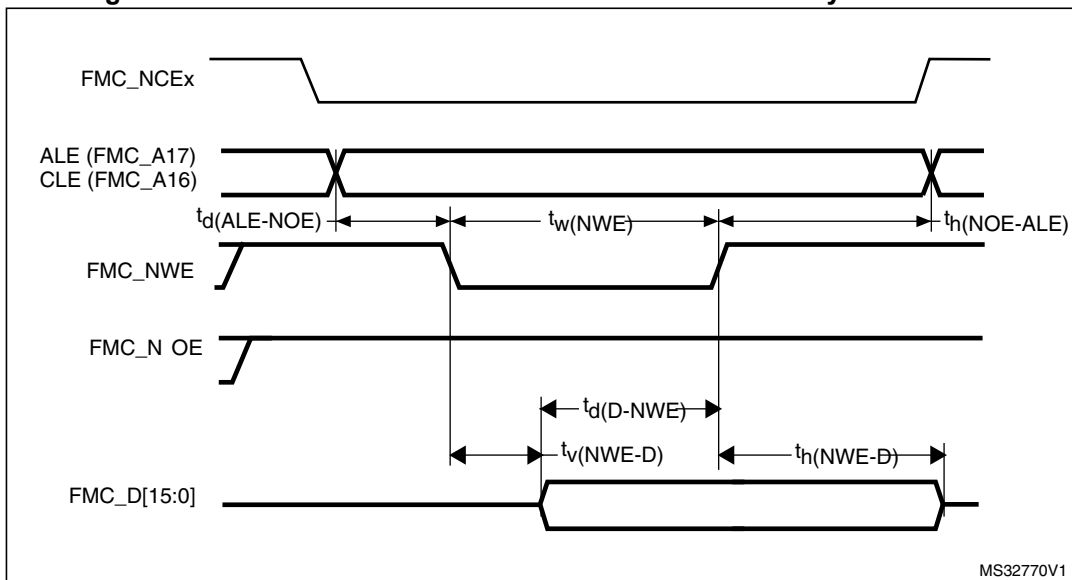


Figure 71. NAND controller waveforms for common memory read access



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Figure 72. NAND controller waveforms for common memory write access



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Table 112. Switching characteristics for NAND Flash read cycles⁽¹⁾

Symbol	Parameter	Min	Max	Unit
$t_w(\text{NOE})$	FMC_NOE low width	$4T_{\text{HCLK}} - 0.5$	$4T_{\text{HCLK}} + 0.5$	ns
$t_{su}(\text{D-NOE})$	FMC_D[15-0] valid data before FMC_NOE high	11	-	
$t_h(\text{NOE-D})$	FMC_D[15-0] valid data after FMC_NOE high	0	-	
$t_d(\text{ALE-NOE})$	FMC_ALE valid before FMC_NOE low	-	$3T_{\text{HCLK}} + 1$	
$t_h(\text{NOE-ALE})$	FMC_NWE high to FMC_ALE invalid	$4T_{\text{HCLK}} - 2$	-	

1. Guaranteed by characterization results.

5.3.35 DFSDM timing diagrams

Figure 80. Channel transceiver timing diagrams

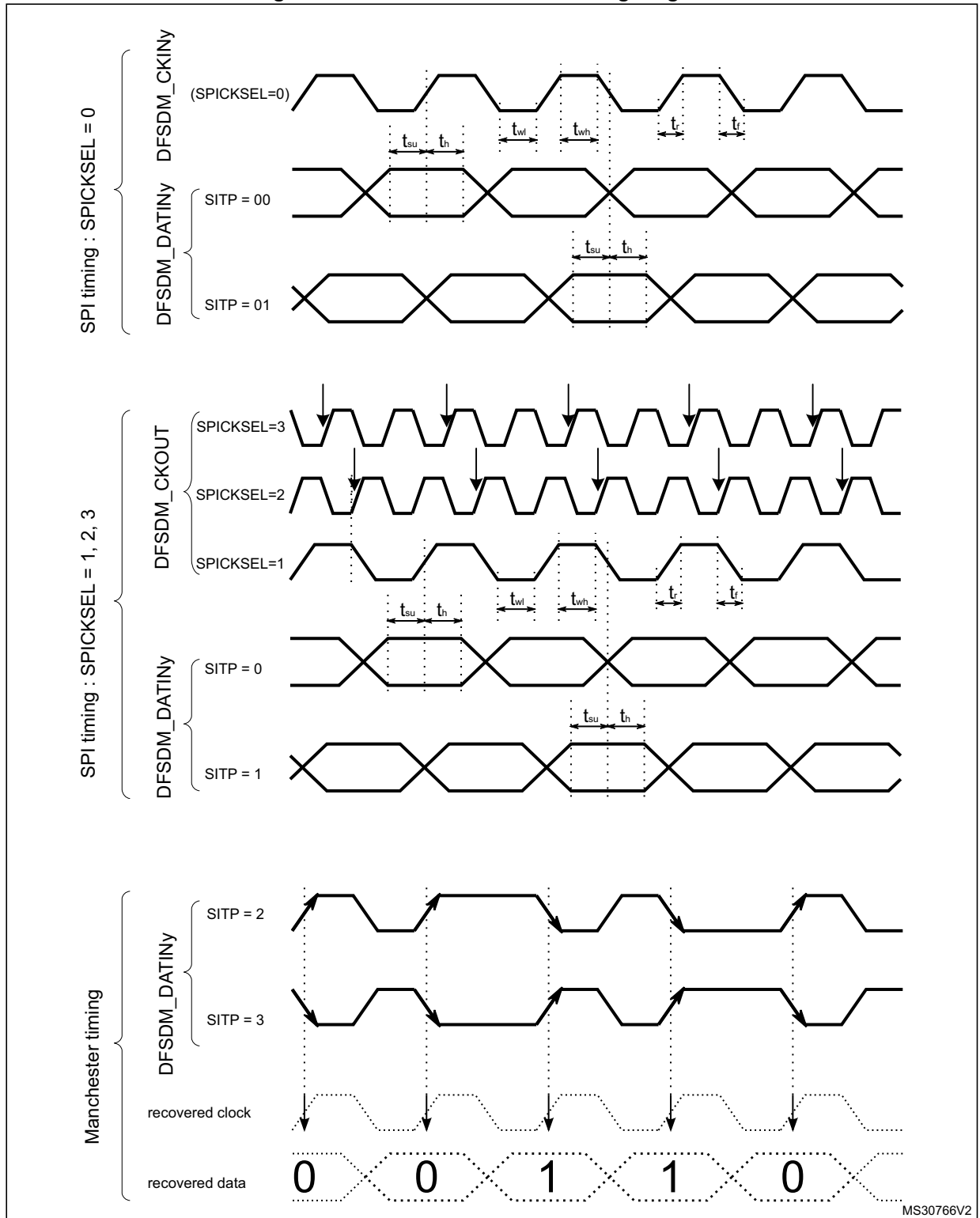


Table 126. LQFP144, 20 x 20 mm, 144-pin low-profile quad flat package mechanical data

Symbol	millimeters			inches ⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.170	0.220	0.270	0.0067	0.0087	0.0106
c	0.090	-	0.200	0.0035	-	0.0079
D	21.800	22.000	22.200	0.8583	0.8661	0.874
D1	19.800	20.000	20.200	0.7795	0.7874	0.7953
D3	-	17.500	-	-	0.689	-
E	21.800	22.000	22.200	0.8583	0.8661	0.8740
E1	19.800	20.000	20.200	0.7795	0.7874	0.7953
E3	-	17.500	-	-	0.6890	-
e	-	0.500	-	-	0.0197	-
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
k	0°	3.5°	7°	0°	3.5°	7°
ccc	-	-	0.080	-	-	0.0031

1. Values in inches are converted from mm and rounded to 4 decimal digits.